## Notice of References Cited Application/Control No. 10/662,394 Examiner Wai Lun Leung Applicant(s)/Patent Under Reexamination AKIYAMA ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*	-	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,512,612 B1	01-2003	Fatehi et al.	398/49
*	В	US-6,154,273 A	11-2000	Suzuki, Yasuo	356/73.1
*	C	US-6,885,820 B2	04-2005	Eder et al.	398/26
*	D	US-6,859,268 B2	02-2005	Chou et al.	356/73.1
*	Е	US-6,813,021 B2	11-2004	Chung et al.	356/364
	F	US-	,		
	G	US-			
	Н	US-			
	1	US-			
	j	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N.					
	0					·
	Р					
	Q					
	R					
	S				·	
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	υ	Morkel, P.R., "PMD-induced BER penalties in optically-amplified IM/DD lightwave systems", IEEE Electronics Letters, 12 May 1994, Vol 30, Iss 10, page 806-807
	٧	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.